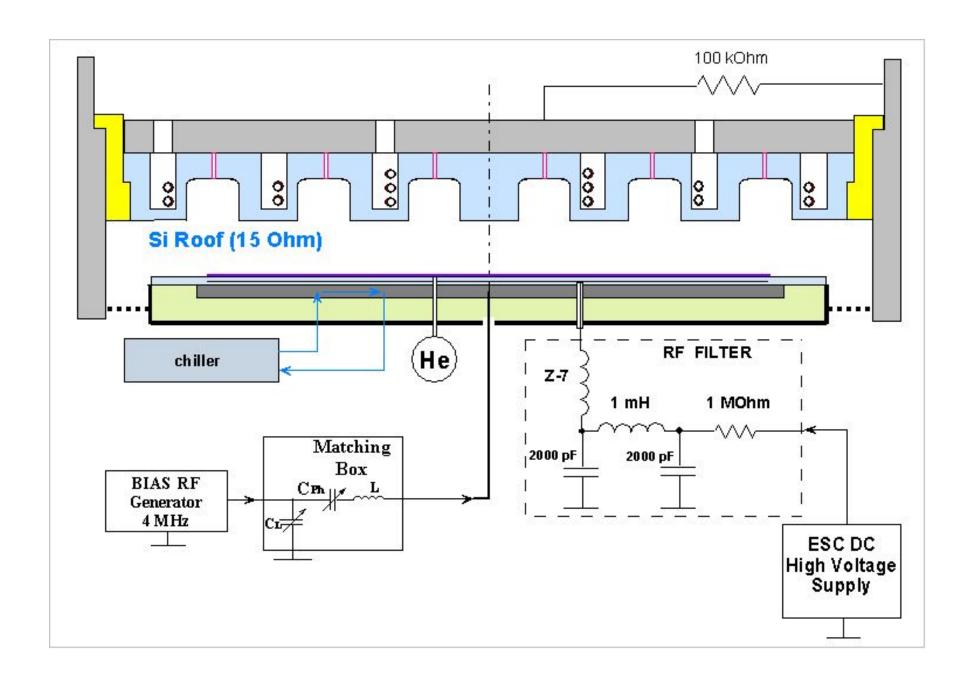
Lift up hole RF breakdown

SE-4000 Experimental

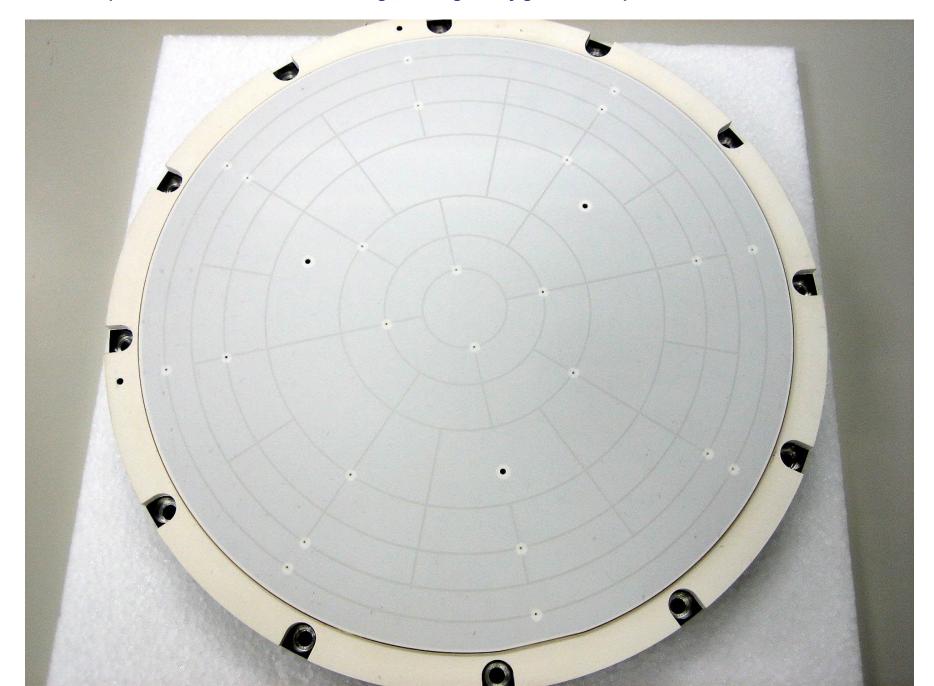
2006.06.27 ~ 2006.07.14 Old type cathode block was checked by high RF voltage bias (up to 8200 Vp-p)

Cathode: N4X05 - 2310

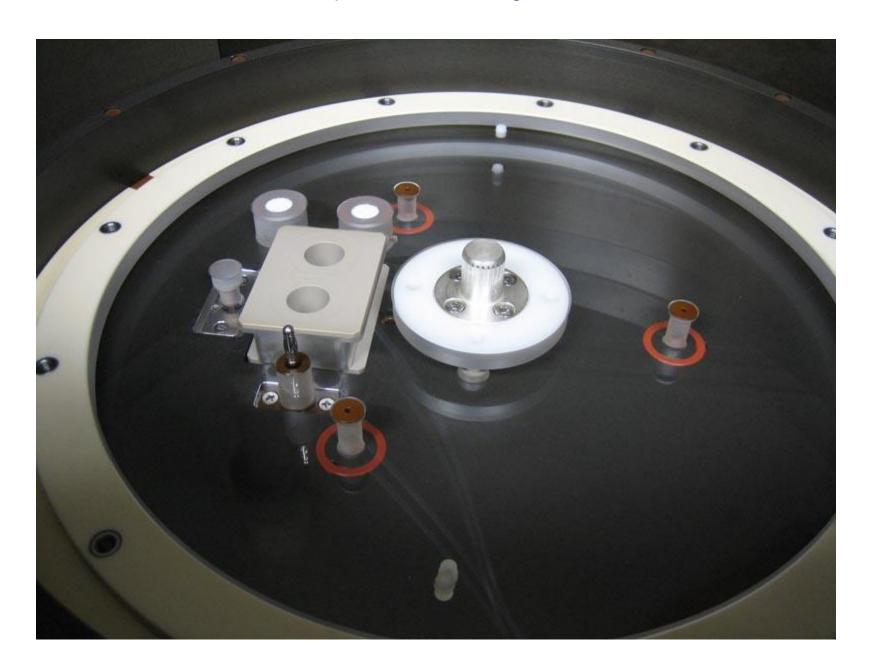
Standard connection was used in this experiments: RF power - to base electrode, DC high voltage – to ESC was applied.



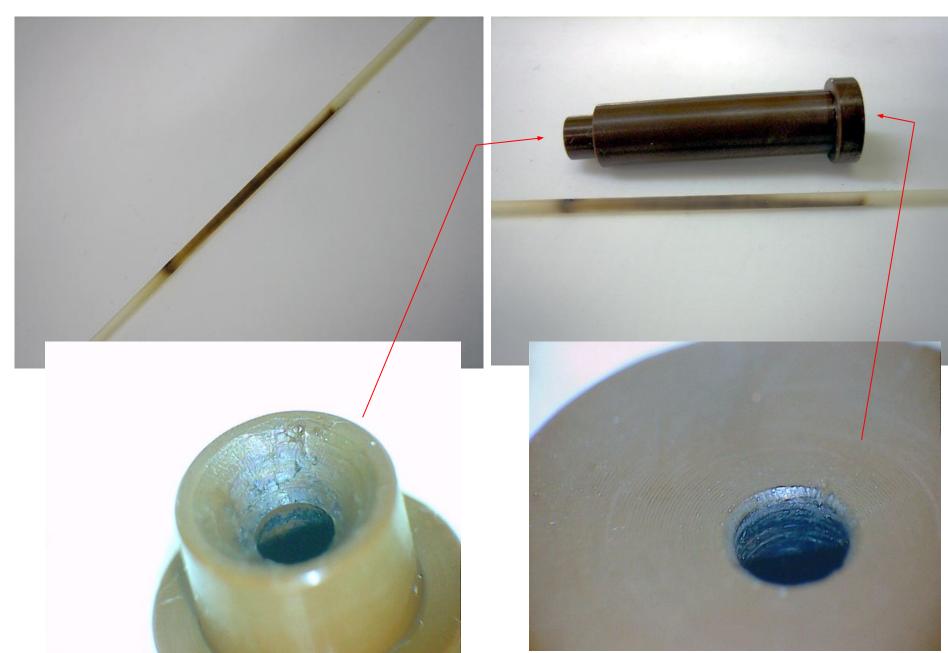
After experiment ESC surface has no damage, although many gas hole low power breakdowns occurred



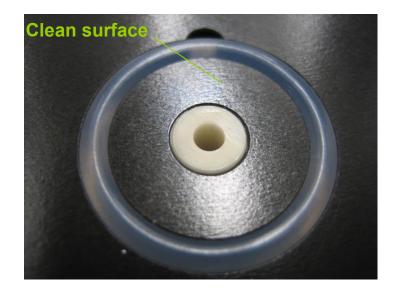
Under cathode parts has no damage too.

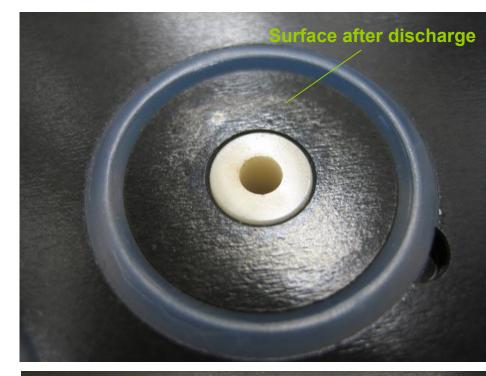


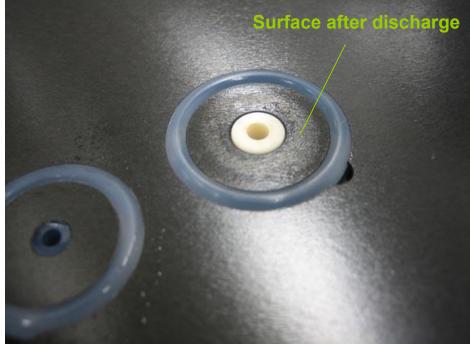
But one lift up hole and lift up pin has traces of RF capacitive discharge



Cathode bottom surface around this lift up hole has traces of RF capacitive discharge too.







Position of capacitive discharge inside lift up hole

V.Menagarishvili

2006/07/24

